

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re U.S. Patent Application of:

Robit DUBEY

Serial No.

Filed: July 10, 2003

For: IMPROVED BOUNDARY SCAN OF
INTEGRATED CIRCUITS

Examiner:

Art Unit:

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
Alexandria, VA 22313-1450

Sir:

Applicant hereby submits for filing under 37 CFR 1.97 a disclosure statement. In submitting these references, no representation is made or implied that the references are or are not material to the examination of this application. The patents, publications or other information of which Applicant is presently aware are listed in Form PTO/SB/08A submitted herewith. Copies of all such patents and publications are enclosed.

No fee is believed due. However, any fee deficiency associated with this submittal may be charged to Deposit Account No. 50-1123.

Respectfully submitted,



July 10, 2003

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PTO/SB/08A (10/01) (Substitute for form 1449A/PTO)		ATTY. DOCKET NO. 01-IND-243		APPLICATION NO	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary) Sheet <u>1</u> of <u>1</u>		FIRST NAMED INVENTOR: Robit DUBEY			
		FILING DATE July 10, 2003		ART UNIT	

U.S. PATENT DOCUMENTS					
Examiner Initials	Cite No.	Document No. No. – Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Doc	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		6,266,793	07-24-2001	MOZDZEN ET AL.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No.	Foreign Patent Doc cntry code – No. – Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Doc	Pages, Columns. Lines Where Relevant Passages or Relevant Figures Appear	TRANSLATION

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS		
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s) publisher, city and/or country where published
		"IEEE Standard Test Access Port and Boundary-Scan Architecture" © 2001, IEEE, Inc., New York, NY, USA

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